

**Search Notes**

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VAN T. PHAM

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YONEZAWA, MINORU

Art Unit

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**SEARCHED**

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369	44.29, 44.32.	7/19/2006	VP

**INTERFERENCE SEARCHED**

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**SEARCH NOTES  
(INCLUDING SEARCH STRATEGY)**

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East (PGPUB; USPAT; USOCR;EPO;JPO;DERWENT;IBM_T DB)  369 (text search only see search history printout).	7/19/2006	VP